

# 2327GN-VB Datasheet

# P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) Typ.	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
	0.046 at V <sub>GS</sub> = - 10 V	- 5.6				
- 30	0.049 at V <sub>GS</sub> = - 6 V	- 5	11.4 nC			
	0.054 at V <sub>GS</sub> = - 4.5 V	-4.5				

#### FEATURES

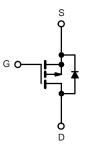
- TrenchFET<sup>®</sup> Power MOSFET
- 100 % R<sub>g</sub> Tested

### APPLICATIONS

- For Mobile Computing
  Load Switch
  - Notebook Adaptor Switch
  - DC/DC Converter



		(SOT-23) TO-236		
G [ s [	1 2		3	D
		Top View		



P-Channel MOSFET

Parameter    Drain-Source Voltage    Gate-Source Voltage		Symbol	Limit	Unit	
		V <sub>DS</sub>	- 30	V	
		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		- 5.6		
Continuous Drain Current (T. 450 °C)	T <sub>C</sub> = 70 °C	1.	- 5.1		
Continuous Drain Current ( $T_J = 150 \ ^{\circ}C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 5.4 <sup>b,c</sup>		
	T <sub>A</sub> = 70 °C		- 4.3 <sup>b,c</sup>	А	
Pulsed Drain Current (t = 100 µs)		I <sub>DM</sub>	- 18		
Contineuro Source Drein Diede Current	T <sub>C</sub> = 25 °C		- 2.1		
Continous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 1 <sup>b,c</sup>		
	T <sub>C</sub> = 25 °C		2.5		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C		1.6	10/	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	1.25 <sup>b,c</sup>	W	
	T <sub>A</sub> = 70 °C	1	0.8 <sup>b,c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stq</sub>	- 55 to 150	°C	

#### THERMAL RESISTANCE RATINGS

	Symbol	Typical	Maximum	Unit			
$t \le 5 s$	R <sub>thJA</sub>	75	100	°C/W			
Steady State	R <sub>thJF</sub>	40	50	0/11			
-	t ≤ 5 s	Symbol        t ≤ 5 s      R <sub>thJA</sub>	SymbolTypical $t \le 5$ s $R_{thJA}$ 75Checky StateP40	SymbolTypicalMaximum $t \le 5$ s $R_{thJA}$ 75100Cheady StateD4050			

Notes:

a. Based on T<sub>C</sub> = 25 °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166  $^{\circ}\text{C/W}.$ 

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<b>SPECIFICATIONS</b> ( $T_J = 25 \text{ °C}$ ,						L	
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = - 250 μA	- 30	1		V	
Drain-Source Breakdown Voltage V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>	VGS - 0 V, ID - 200 µA	- 30	- 19		mV/°C	
		I <sub>D</sub> = - 250 μA		- 19			
V <sub>GS(th)</sub> Temperature Coefficient Gate-Source Threshold Voltage	$\Delta V_{GS(th)}/T_J$	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = - 250 μA	- 0.5	4	- 2.0	V	
<b>.</b>	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $V_{DS} = 200 \mu$ K $V_{DS} = 0 \text{V}$ , $V_{GS} = \pm 20 \text{V}$	- 0.5		- 2.0 ± 100	v nA	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = -20 \text{ V}$					
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_1 = 55 \text{ °C}$			- 1	μA	
On-State Drain Current <sup>a</sup>		$v_{DS} = -50 \text{ V}, v_{GS} = 0 \text{ V}, 1_{J} = 55 \text{ C}$ $V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 2.5		- 5	A	
	I <sub>D(on)</sub>	$V_{\rm GS} = -10 \text{ V}, \text{ I}_{\rm D} = -4.4 \text{ A}$	- 2.5	0.046		A	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -6 V, I_D = -4 A$		0.046		_	
Drain-Source On-State Resistance		$V_{GS} = -6.0 \text{ V}, I_D = -4.7 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -3.6 \text{ A}$		0.049		Ω	
Forward Transconductance <sup>a</sup>	<u> </u>	$V_{GS} = -4.5 \text{ V}, \text{ ID} = -3.6 \text{ A}$ $V_{DS} = -15 \text{ V}, \text{ ID} = -3.4 \text{ A}$		0.054		S	
Dynamic <sup>b</sup>	9 <sub>fs</sub>	VDS = - 13 V, IB = - 3.4 A		18		3	
-	C <sub>iss</sub>			1205	*		
Input Capacitance		V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		1295		- ~-	
Output Capacitance	C <sub>oss</sub>	$v_{\rm DS} = -13 v, v_{\rm GS} = 0 v, t = 1.0012$		150		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 5.4 A		130	20		
Total Gate Charge	Qg	$v_{DS} = -15 v, v_{GS} = -10 v, I_D = -5.4 A$		24			
Gate-Source Charge	Q <sub>gs</sub>			11.4 3.4	17	nC	
Gate-Drain Charge	Q <sub>gs</sub> Q <sub>gd</sub>	$V_{DS}$ = - 15 V, $V_{GS}$ = - 4.5 V, $I_{D}$ = - 5.4 A		3.4			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	1.5	7.7	15.4	Ω	
Turn-On Delay Time			1.5	13	20	52	
Rise Time	t <sub>d(on)</sub>	V - 15 V P - 25 O		4			
	t <sub>r</sub>	$V_{DD}$ = - 15 V, R <sub>L</sub> = 3.5 Ω I <sub>D</sub> ≅ - 4.3 A, V <sub>GEN</sub> = - 10 V, R <sub>g</sub> = 1 Ω			8 57	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	D = 1000, 000 = 1000, 100 = 122		38	57	-	
Fall Time Turn-On Delay Time	t <sub>f</sub>			6 28	12 42	ns	
Rise Time	t <sub>d(on)</sub>			20 16		-	
	t <sub>r</sub>	$V_{DD} = -15 \text{ V}, \text{ R}_{\text{L}} = 3.5 \Omega$ $\text{I}_{\text{D}} \cong -4.3 \text{ A}, \text{ V}_{\text{GEN}} = -4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$			24 45	-	
Turn-Off Delay Time Fall Time	t <sub>d(off)</sub>	$D = -4.3 \text{ A}, V_{\text{GEN}} = -4.3 \text{ V}, N_{\text{g}} = 1.22$		30	45	-	
Drain-Source Body Diode Characteristic	t <sub>f</sub>			10	20		
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C		1	- 2.1		
Pulse Diode Forward Current (t = $100 \mu$ s)		16-20 0			- 2.1	A	
	I <sub>SM</sub> V <sub>SD</sub>	I <sub>S</sub> = - 4.3 A, V <sub>GS</sub> = 0 V		- 0.8	- 00	V	
Body Diode Voltage		νς τ.ο Λ, ν <sub>GS</sub> - υ ν				-	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			15	23	ns	

Notes:

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

Body Diode Reverse Recovery Charge

Reverse Recovery Fall Time

Reverse Recovery Rise Time

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

 $I_F = -4.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ }^\circ\text{C}$ 

Qrr

ta

 $t_{b}$ 

7

8

7

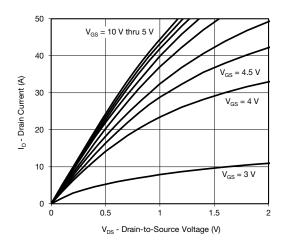
14

nC

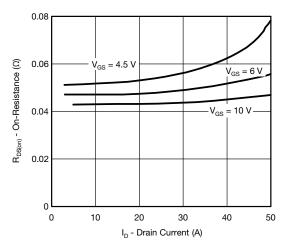
ns



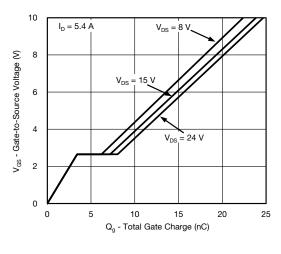




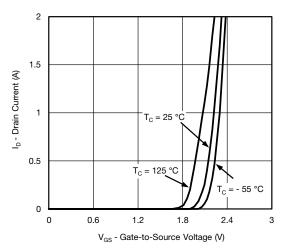
**Output Characteristics** 



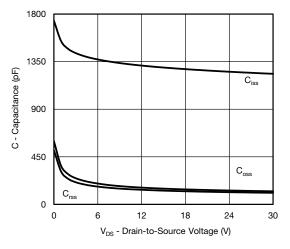
**On-Resistance vs. Drain Current** 



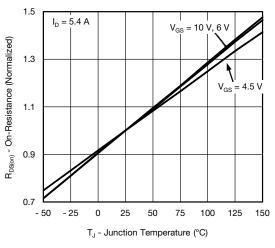
**Gate Charge** 



**Transfer Characteristics** 

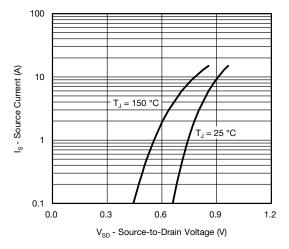






**On-Resistance vs. Junction Temperature** 



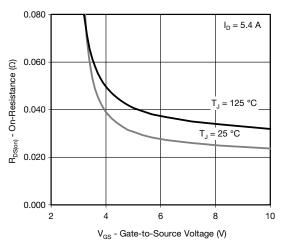


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

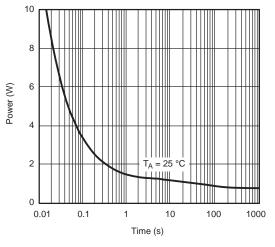




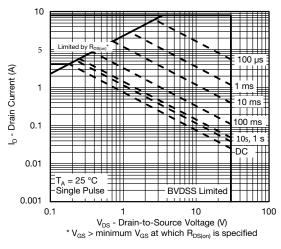
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



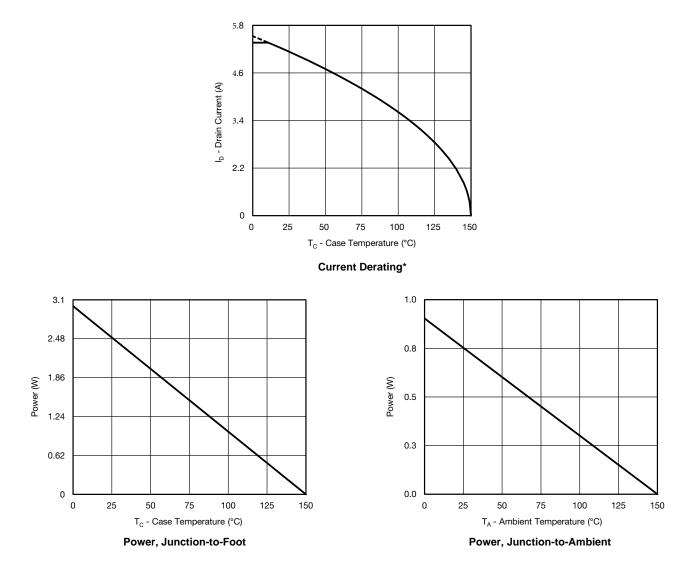
Single Pulse Power (Junction-to-Ambient)



Safe Operating Area, Junction-to-Ambient



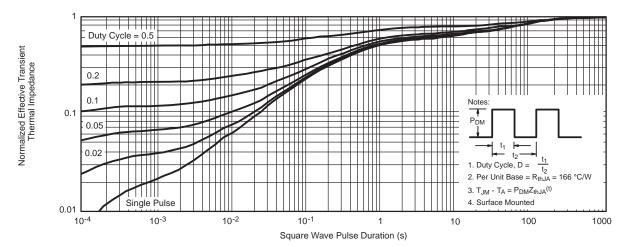
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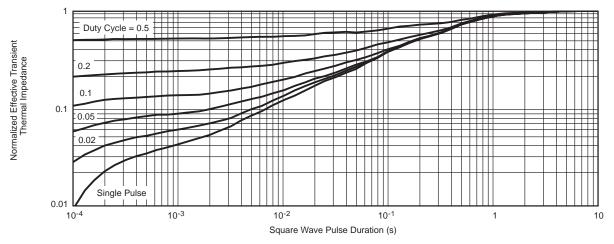
\* The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



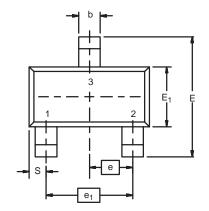
Normalized Thermal Transient Impedance, Junction-to-Ambient

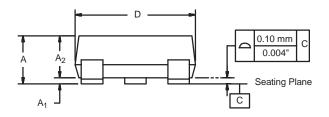


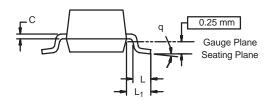
Normalized Thermal Transient Impedance, Junction-to-Foot



## SOT-23 (TO-236): 3-LEAD



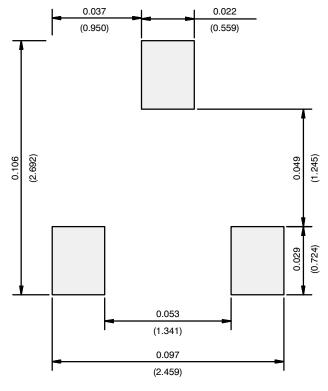




A A A <sub>1</sub>	<b>Min</b> 0.89	Max	Min	Мах	
	0.80			max	
Δ.	0.03	1.12	0.035	0.044	
~1	0.01	0.10	0.0004	0.004	
A <sub>2</sub>	0.88	1.02	0.0346	0.040	
b	0.35	0.50	0.014	0.020	
с	0.085	0.18	0.003	0.007	
D	2.80	3.04	0.110	0.120	
E	2.10	2.64	0.083	0.104	
E <sub>1</sub>	1.20	1.40	0.047	0.055	
е	0.95	0.95 BSC 0.0374 Ref		Ref	
e <sub>1</sub>	1.90 BSC		0.0748 Ref		
L	0.40	0.60	0.016	0.024	
L <sub>1</sub>	0.64 Ref		0.025 Ref		
S	0.50 Ref		0.020 Ref		
q	3°	8°	3°	8°	



#### **RECOMMENDED MINIMUM PADS FOR SOT-23**



Recommended Minimum Pads Dimensions in Inches/(mm)



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